

09/686895

	L #	Hits	EAST Search Text	DBs	Time Stamp	Type
1	L1	3380	wafer WITH fragment\$6	USPAT; US-PGPU B; EPO; JPO; DERWEN T; IBM_TDB	2004/03/10 20:06	BRS
2	L2	66	L1 SAME (camera OR image OR video OR picture OR photo OR photograph)	USPAT; US-PGPU B; EPO; JPO; DERWEN T; IBM_TDB	2004/03/10 20:07	BRS
3	FAMILY	1	2000-364715.NRAN.	DERWEN T	2004/03/10 20:08	BRS
4	L4	21	("4352016" "4652757" "4659220" "4812664" "5383018" "5446824" "5592295" "5598341" "5618380" "5622595" "5643404" "5659630" "5660472" "5708557" "5708755" "5850466" "5909276" "5938335" "6049148" "6064429"	USPAT	2004/03/10 20:12	BRS

	1	Document ID	Source	Issue Date	Title	Current OR	Inventor	2	3	4	5
1	<input checked="" type="checkbox"/>	WO 200022655 A	DERWENT	20030507	Wafer fragments analyzing system for semiconductor production, has image acquisition device to acquire image of wafer edge portion where illumination source generates back-illuminating radiation for wafer		AHMAD, W R et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2	<input checked="" type="checkbox"/>	US 6535628 B2	USPAT	20030318	Detection of wafer fragments in a wafer processing apparatus	382/149	Smargiassi, Eugene et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3	<input checked="" type="checkbox"/>	US 20030202178 A1	US-PG PUB	20031030	Semiconductor wafer inspection apparatus	356/237.2	Tsuji, Haruyuki et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input checked="" type="checkbox"/>
4	<input checked="" type="checkbox"/>	US 20010043735 A1	US-PG PUB	20011122	DETECTION OF WAFER FRAGMENTS IN A WAFER PROCESSING	382/149	SMARGIASSI, EUGENE et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
5	<input type="checkbox"/>	CN 1405853 A	DERWENT	20030326	Method for tracing wafer boundary		XU, Q	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input checked="" type="checkbox"/>
6	<input checked="" type="checkbox"/>	US 6064429 A	USPAT	20000516	Foreign object video detection and alert system	348/128	Belk, John Huntley et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
7	<input type="checkbox"/>	US 5909276 A	USPAT	19990601	Optical inspection module and method for detecting particles and defects on substrates in integrated process tools	356/237.2	Kinney, Patrick D. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
8	<input type="checkbox"/>	US 5659630 A	USPAT	19970819	Advanced manufacturing inspection system	382/149	Forslund, Donald Charles	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
9	<input type="checkbox"/>	US 5592295 A	USPAT	19970107	Apparatus and method for semiconductor wafer edge inspection	356/426	Stanton, Leslie G. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
10	<input type="checkbox"/>	US 4352016 A	USPAT	19820928	Method and apparatus for determining the quality of a semiconductor surface	250/358.1	Duffy, Michael T. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
11	<input type="checkbox"/>	US 4652757 A	USPAT	19870324	Method and apparatus for optically determining defects in a semiconductor material	250/360.1	Carver, Gary E.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
12	<input type="checkbox"/>	US 4659220 A	USPAT	19870421	Optical inspection system for semiconductor wafers	356/237.5	Bronte, Joseph J. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
13	<input type="checkbox"/>	US 4812664 A	USPAT	19890314	Apparatus for scanning a flat surface to detect defects	250/559.18	Borden, Peter G.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>